MAR 0 5 2007 OFFICE OF PETITIONS

EXHIBIT A

U.S. SERIAL NO.: 10/521,619

ASSIGNMENT OF PATENTS

This Assignment of Patents (this "Assignment") is effective as of the Initial Closing Date (as defined in the Asset Purchase Agreement (the "Asset Purchase Agreement"), dated as of October 10, 2003, by and among ASML Holding N.V., a Dutch company ("Parent"), ASML U.S., Inc., a Delaware corporation and a wholly-owned subsidiary of Parent ("Seller U.S."), and the other affiliates of Seller U.S. party thereto (together with all of the foregoing parties, each a "Seller" and collectively the "Sellers"), on the one hand, and Thermal Acquisition Corp., a Delaware corporation ("Buyer")). Capitalized terms used herein but not defined shall have the meanings ascribed to such terms in the Asset Purchase Agreement.

WHEREAS, upon the terms and subject to the conditions in the Asset Purchase Agreement, Sellers have agreed to assign and transfer to Buyer, among other things, certain Patents (as defined below);

WHERBAS, in order to further effect the assignment and transfer of such Patents, Buyer has requested that Seller U.S. execute and deliver to Buyer this Assignment;

NOW, THEREFORB, for good and valuable consideration, the receipt and sufficiency of which is hereby acknowledged:

1. Sellers agree to and hereby do assign, sell, transfer, grant and convey to Buyer, its successors and assigns, all of Sellers' worldwide right, title and interest in and to all Patents listed on schedule 3.18(a)(i) of the Disclosure Schedule and all causes of action, demands, judgments, claims, or other similar rights of Sellers relating primarily to such Patents.

"Patents" shall mean all U.S. and foreign patents and applications therefor and all reissues, divisions, renewals, extensions, provisionals, continuations and continuations-in-part thereof.

- 2. Sellers authorize and request the United States Patent and Trademark Office and head of any foreign patent office to issue all patent registrations which may issue on any applications for any Patents to Buyer, its successors and assigns, in accordance with this Assignment.
- 3. Promptly upon the request of Buyer, Sellers shall execute such documents and perform such actions as may be necessary to perfect the assignment of rights contained in this Assignment.
- 4. Nothing herein shall affect, or be deemed to affect, the representations, warranties, covenants, and indemnities contained in the Asset Purchase Agreement.
- 5. This Assignment may be executed in one or more counterparts and signature may be delivered by facsimile, each of which shall be deemed an original, but all of which together shall constitute one and the same instrument.

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IN WITNESS WHEREOF, Seller U.S. has caused this instrument to be executed by its duly authorized corporate officer as of the Closing Date:

ASML U.S., Inc.

Ву: .

Name: C. Douglas Marsh

Title: Vice President Business Integration

& U.S. Institutional Relations

ACKNOWLEDGED AND AGREED:

Thermal Acquisition Corp., a Delaware Corporation

Ву:

Name: Jerauld Cutini

Title: President and Chief Executive Officer

IN WITNESS WHEREOF, Seller U.S. has caused this instrument to be executed by its duly authorized corporate officer as of the Closing Date.

ASML U.S., Inc.

By:

Name: C. Douglas Marsh

Title: Vice President Business Integration & U.S. Institutional Relations

ACKNOWLEDGED AND AGREED:

Thermal Acquisition Corp., a Delaware Corporation

Name: Jerauld Cutini

Title: President and Chief Executive Officer

DISCLOSURE SCHEDULES

SCHEDULE 3.18(a)(i)

The following Patents:

RECEIVED

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OFFICE OF PETITIONS

Attachment 1 to Disclosure Schedule 3.18(a)(I)

Refe	Reference No.			1		·	
				IMG/Inventors	Serial No./	Patent No./	
∢	16178	. 9	- AST	DEPOSITION OF STREET	Filling Date 07/068,727	Intre Date	Countries
FA ·	16178	ė. S	A.T.		06/29/87	07/04/89	·
∀	16178	7	AST	2	06/14/86	12/26/97	Japan
FA	16178	7-32	AT	-	10/27/87	4,834,022	·
4	16178	00	45	e	07/14/86	2076448 08/09/96	Japan
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FA .	44048		AST		63-307653 12/05/88	2930960 05/21/09	Japan
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٠	Patent No.	Issue Date	Abandoned			Abandoned in favor	(A-47444-1)	Abandoned	Abandoned		pergoggery	2222416/ 03/03/03	Abandoned				Abandoned in favor	(A-4744-2)	Abandoned in favor	(A-47444-3)	Abandoned per client ltr 09/14/98	5,088,773	5.136.975	08/11/92	5,113,789
	Serfal No./	Filing Date	09/16/87		•	07/238,826 08/31/88		P39287653	-	08/31/89	08/31/89	8919291.8 08/24/89		Closed	Closed		07/798,829 11/22/91		07/991,500 12/17/92	000000000000000000000000000000000000000	10/27/94	07/570,122 08/17/90	3		07/513,807
	Title/Inventors	BOROSILICATE GLASS FILMS FOR MITTER ENTER	METALLIZATION STRUCTURES IN SEMICONDICTOR DESIGNATION	METHOD FOR IMPROVING THE STEP COVER A CH	CHRACAT WAS CROUTS	SILANE/Gralenski	CHEMICAL VAPOR DEPOSITION LISTING PROFESSIONAL	Gralenski	CHEMICAL VAPOR DEPOSITION USING DISILANE	CHEMICAL VAPOR DEPOSITION USING DISILANE	PROCESSES USING DIST. ANTER.	Cigural Control Control	CHEMICAL VAPOR DEBOSETION TITLE	SILANE/Gralenski	CHEMICAL VAPOR DEPOSITION USING DYED	CHEMICAL VAPOR DIPPOSITION TIMES	Gralenski	CHEMICAL VAPOR DEPOSITION INSING PIET 43TH	Gralenski	CHEMICAL VAPOR DEPOSITION USING DISTI ANE/	HERCIRICALLY INSTIT ATER PIPE COMPANY	_			
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	52354	M	AT.	SELP CLEANING FLOW CONTROL OR PRICEIN		Abandoned		_
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	53835		A	U-SHAPED HEATER LINES/Walker	07/601.261	Abandoned		
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'n	53859		AJT	LIQUID LEVEL SENSOR ASSEMBLY/Goodnich	07/601 408	****		
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Title/Inventors	A THIN FILM SEMICONDUCTOR DRIVER AND	METHOD/Hunda A THIN FILM SEMICONDITITION DEFICES.	MBTHOD/Hards	SUBSTRATE FOR A THIN FILM Handa	METHOD OF MANUFACTURING A GLASS	METHOD OF MANUFACTURING A GI ASS	SUBSTRATE FOR A THIN FILMHanda METHOD OF WANTED A THIN FILMHAND	SEMICONDUCTOR DEVICE HAVING SIDE WALLS, AND HEARD HAMME, HAMME	METHOD OF MANI RACTI BRIG SEES	SEMICONDUCTOR WITH SIDE WALLS, Harada, Hatturi	METHOD OF MANUFACTI IRING SIDE WILLS	SEMICONDUCTOR DEVICE HAVING SIDE WALLS AND Herada, Hattori		THE DEPOSITION OF SICHALIA	SINGLE BODY, INJECTOR AND METHOD FOR	CELLY LANGES TO A SURFACE/Dedominey	SINGLE BODY INJECTOR FOR DELIVERING GASES	SINGLE BODY INJECTOR FOR DET FITTER FOR	TO A SURFACE/Dedominey 071	TO A SURPACED COURSE OR DELIVERING GASES	INGLE BODY INJECTOR FOR DELIVERING GASES	C. A. SUKEACE/Dedominey
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	Title/Inventors	SINGLE BODY INJECTOR FOR DELIVERING GASES	TO A SURFACE/Dedomings	TO A SURFACE/Dedoming	SINGLE BODY. INJECTOR FOR DELIVERING GASES	SING BOLD HER	MARCIOR INECTOR	SINGLE BODY INDECTOR FOR DRI INFERING CAMER	TO A SURFACE/Dedominey.	MINGLE BODY INTECTOR FOR DELIVERING GASES TO A SURFACE/Dedoming	SINGLE BODY INTECTOR AND AGENCE TO	DELIVERING GASES TO A SURFACE/Dedoming,	Transmit William	METHOD OF MANUFACTIBING AN INTECTION FOR	CHEMICAL VAPOR DEPOSITION PROCESSING/Dedoming Gralement Mail.	Tallifu Transcript (TO A SURFACEAMING, Dobkin			SINGLE BODY. INIECTOR FOR DELIVERING GASES TO A SURFACEMHIEF DANNIE	SINGLE BODY INJECTOR AND DEBOGRAPOST	CHAMBER Mile, Dobkin	-	
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FA	59471	4-TF	ATT	SINGLE BODY INTECTOR AND DEPOSITION	12/21/00			
FA	59471	4KR	AT	SINGLE BODY INTECTOR AND DEPOSITION	2007/10/98		Japan	
FA	59471	4-8G	ATT	SINGLE BODY INTECTOR AND DEPOSITION	07/10/98	355058 09/29/02	South Korea	T
毘	59471	4世	15	SINGLE BODY INTECTOR AND DEPOSITION	07/10/98	03/04/02	Singapore	
∢	59471	5	A 17	CHAMBER/Miller, et al.	98933329.9		Buropo	
			MSS SMF	CHAMBERAMINE, Dobkin	09/757,542 01/09/01 Divisional of	6,521,048 02/18/03		
4	60164		ATT	WRITHOD OF BODY WAS	09/113,823 07/10/98			
¥a	77.09	-	MSS ·	MATERIAL/Fry, Lightfoot, Lomond	08/447,809	5,668,063		
			AJT.	METHOD OF PLANARIZING A LAYER OF MATERIAL Fry, Lighthot Lomma	708269/97	76/91/60	County V	
4		<u> </u>	AJT MESS	METHOD OF PLANARIZING A LAYER OF	05/06/96 8-535689			
田		E E	AJŢ	METHOD OF PLANARIZING A LAYER OF	05/06/96	Abond	nagar	
丑	60164	2		IOD OF FLANARIZING A LAYER OF RIALPRY Lightfoot 1	36,06375		Europe	
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	rence NC	,		Title/Inventors	Serial No.	Patent No./	Foreign .
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∢	62732	-	1 4	PROTECTIVE GAS SHIELD FOR CHEMICAL VAPOR	02/13/97	(A-62732-1)	
4	62732	2	ATT	DEPOSITION APPARATUS		- 5,944,900 08/31/99	
			IEW IEW	2	Closed		
∢	62786		ATT	METHOD OF FORMING DIELECTRIC FILMS WITH REDUCED METAL CONTAMINA TOWN		Abandoned in favor	
V	62786		. 25		12/15/95	of 08/599,092 (A-62786-1)	· ·
			MSS	REDUCED METAL CONTAMINATION/Cervalheira	02/07/96 CIP of 08/573 318	Abandoned	
FA	98/29	2	A.T.		Filed 12/15/95		
FA	62786	<u>1.</u>	ATT	DUCED METAL CONTAMINATION/Carvalheira	12/11/96		China
FA	78769	2	MSS	UCED METAL CONTAMINATION/Carvalheira	9-522910 12/11/96		Japan
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4	62998			m	12/11/96		FCT
4	63007			METHOD OF IMPROVING DEPOSITION THICKNESS		Topic Control	
¥	80059			MIZING OF SIGS FILM CONFORMALITY IN	200,100/80		
1926	L71035Aree (45)			OSPHERIC PRESSURB CHEMICAL VAPOR		756,55%,0	

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	_	_	JEEN	DEPOSITION	Filing Date	Inne Date	Countries
F	63008	AL 92			02/18/97	01/06/99	
			NEW Y	TEOSAS APCYD	87012245	107673	Taiwan
<u>E</u>	63008	∞ . ™.		OPTIMIZATION OF SIO2 FILM CONFORMALITY IN	02/18/98 PCT/TE09/00040	02/02/00	
		_		ATMOSPHERIC PRESSURE CHEMICAL VAPOR DEPOSITION	02/17/98	Absordoned.	PCT
<	63265	<u></u>		LOW K DIELECTRICS PREPARED FROM CROSS-LINKED PRYS (7. BEYEN F.	08/679,864	5,925,420	·
肚	63265	S PC	i	CROSSLINKED AROMATIC POLYMERS SA LOW E	07/16/96 PCT/US97/10575	07/20/99 Abandoned	Ę
₹	633.47		AJT	A METHOD OF PLANARIZING A DIELECTRIC LAYER WITH REDUCED HYDROGEN DIFFUSION/	07/14/97 Clased		
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			IEW.	HIGH TEMPERATURE ROLLER MODULE/Kleiner	09/019,349	5,976,258	
∢	63661		AJT MSS	ENDED	Closed	11/02/99	
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			MSS		08/823,655 03/11/97	5,916,378 06,22/99	
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PA	63665	2 80	AST	METHOD OF CONTAMINATION PERVIOUS				
	_	•	MSS	FORMATION OF ALL OXIDE SURFACE LAYERS/Bulley, Brack	9904262-4 03/06/98	67703	Singapore	T-
¥	63665	<u>A</u>	AT	METHOD OF CONTAMINATION REDUCTION BY FORMATION OF ALL OXIDE SURFACE	87102978 03/02/98	147013 04/15/m2	Taiwan	
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<u>e</u>	63665	<u>5</u>	AJT	METHOD OF CONTAMINATION REDUCTION BY FORMATION OF ALL OXIDE STREAGE	8/04570	Closed	Į.	
⋖	69929		154	LAYERS/Bailoy, Brady FLANGE CLAMP/Mattons, Kamisn	03/06/98:			<u>!</u>
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V.	64725		AT.	NUTROGEN DILUENT GAS FREE OPER ATTON OF		59471-3 and closed		
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			NGS.	APPARATUS FOR PROCESSING A SEMICONDUCTOR SUPERING A	09/018,021 02/02/98	6,026,589 00,222/20		T
4	64873	11 1	AT.	WAFER CARRIER AND SELECTION OF THE DELLEY				
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j				CANADOCIOR SUBSIRATE/Yao, Bailey	Div. of 09/018,021		•	
F.	048/3	ઇ	AT	WAFER CARRIER AND SEMICONDUCTOR APPARATIS FOR THE CONTRACTOR	2319636	Abendoned	Consule	T
1	_	_		SEMICONDUCTOR SUBSTRATE/Yeo, Bailey	02/01/99			
<u> </u>	5/2	3	ASS A	WAFER CARRIER AND SEMICONDUCTOR APPARATHS ROB DEOCRECATO	99802634.4			
10			·	SEMICONDUCTOR SUBSTRATE/Yao, Bailey	02/01/99	:		·
<u> </u>	86/3	¥	MESS	WAFER CARRIER AND SEMICONDUCTOR APPARATUS FOR PROCESSING A	01104936.8	Abandoned	Hong Kong	
FA	64873	月	12	WARRE CARPIER CONTRACTOR SO, Bailey				
		·	MSS	APPARATUS FOR PROCESSING A SEMICONDUCTOR SUBSTRATEAN OF BRIDE	137533 02/01/99	Abandoned	Israel	1
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	c) eg	वे	MSS	WAFER CARRIER AND SEMICONDUCTOR AFPARATUS FOR PROCESSING A SEMICONDUCTOR SEMICONDUCTOR STREET	99905586.6		Europe	
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65583 2-TW AJT FREE FLOATING SHIELD, MSS PROCESSING SYSTEM OF THE PROCE	2-TW AJT MES		FREE FLOATING SHIELD	AND SEMICONDUCTOR	03/31/00 89106510		omino . E
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65965 IL AJT LOW K DIELECTRIC INORG	A-T-		LOW K DIRLECTRIC INORG	ANIC/ORGANIC 1.	139128	Abondon	
			ELECTRICAL FILMS AND METHO	D OF MAKING/Rose; 0	04/15/99	Demography	Israel

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٧	66959	1 6	15	WAFER PROCESSING REACTION HAVING A CAR	Filing Date	Istue Date	Countries	
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<u>a,</u>	67178	∞	Ł¥.	GAS DELIVERY METERING TURKSEN dend V.			. •	
✓	67178		MSS	Hamilton; Ingle; DeSa; Kudriavstev; Peabody	05/21/99			T
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FA	67178		AST		2000-148939			
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	df 7,65/0	A.F.	METHOD FOR PRODUCING HIGHLY CONDUCTIVE	53519/97	7	
			FLUORIDE DOPED INDIUM OXIDE BY APCVD/MANY		Demogramy	Jepan .
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67735	·	AJT MSS	IMPROVED TRENCH ISOLATION PROCESS USING APCYD TEOS; OZONE TO DEPOSIT A TRENCH FILL OXIDE PRIOR TO SIDEWALL LINER OXIDATION GROWTH/Cartis; Rao; Kankin	60/127,520 04/02/99	Closed	
67735		AJT MSS	IMPROVED TRENCH ISOLATION PROCESS USING APCYD TEOS: OZONE TO DEPOSIT A TRENCH FILL OXIDE PRIOR TO SIDEWALL LINER OXIDATION GROWTH/Curis; Reg; Kapia	09/541,395 03/31/00	6,387,764 Issued: 05/14/02	
67735		AJT. MISS	TRENCH ISOLATION PROCESS USING APCVD TEOS:OZONE TO DEPOSIT A TRENCH FILL OXIDE PRIOR TO SIDEWALL LINER OXIDATION GROWTH! Cartis Res; Kapkin	2364975 03/31/00	Abandoned	Cemada
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		AJT MSS		2001-7012564 03/31/00		South Kores
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SERMICONDUCTOR WAFER PROCESSING SYSTEM 14 WITH VERTICALLY-STACKED PROCESS CHAMBERS AND SINGLE-AXIS DUAL-WAFER, TRANSFER SYSTEM/Savage; Managh; Carvalheirs; Trainni; Consentine; Vanghan; Mayer	SSING SYSTEM 145678 OCESS AL-WAPER, t; Carvalheirs;		Abandonod	[srae]

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FA 67	67736 KR	AJT	SEMICONDUCTOR WAFER PROCESSING SYSTEM WITH VERTICALLY-STACKED PROCESS CHAMBERS AND SINGLE-AXIS DUAL-WAFER TRANSFER SYSTEM/Savage; Menagh; Carvalheira;	2001-7012462 03/21/00		South Kores
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₹	68073		ASS	CHEMICAL VAPOR DEPOSITION OF SILICON				
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88628	82	AT	STEM AND METHOD FOR DEPOSITING	60/166.662	782	
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4	2000	7	77.	LOW TEMPERATURE SILICON NITRIDE CVD			•	
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F-71935/MSS (463035-828) 1059128

Ref	Reference No.	9						
				Title/Inventors	Serfal No./	Patent No.	Posset	٢
	L	-	MISS	PROCESS	Filting Date	Issue Date	Countries	
	•	.			08/25/86	01/19/88		_
٧	80689	000	44	PULSE WIDTH MODIL ATTENTION		Abandoned		
			MSS.	SYSTEM FOR CHEMICAL VAPOR DEPOSITION APPARATUS/Johnson: Ellion	06/845,212 .03/27/86	4,728,869		
∢ .	60689		AFF	HOT WALL DIFFUSION FURNACE AND METHOD	CIP of 06/813,915 07/181,787	4.886.954		
V	68910	-	124	METHOD AND ABOVE AND ASSET		12/12/89		
			MSS	PRODUCTS OF CHEMICAL VAPOR DEPOSITION FROM OIL FOR VACITIM PINAPACT	06/029,525 04/12/79	4,228,004 10/14/80		
⋖.	68911		AT	MASS FLOW CONTROL LER DOVIE	06/103 876	7 (20 022		
	68012	1	NEW Y		10/03/80	4,008,855 04/21/87		
	7		WESS	DIFFUSION FURNACE MULTIZONE TEMPERATURE 06/864,676	06/864,676	4,711,989		
¥	68913		AST	WAFER BOAT TO ANGRED TOOL A	. 98/11/20	12/08/87.		
_			MSS	ollowing and an arrange of the state of the	05/16/86 05/16/86	4,728,246 03/01/88		
∀	68914		A-F	WAFER TRANSFER STANDAGE		Abandoned		
			MSS .		07/048,868 05/12/87	4,721,427 01/26/88		
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≮	51689		AJT.	SENSOR FOR BATCH-TYPE	00000	Reinstated	٠.	_
A	91689			JOK/Rediff		Abendoned .		
			MSS	Nguyan BLUCK FLUID DELIVERY SYSTEM	09/388,216	Abandoned		
PA	68916	TW	ASS	LAYERED BLOCK FLUID DELIVERY SYSTEM/Names		146378	1	
FP	91689	2		RED BLOCK FLUID DELIVERY		08/21/01		
7			MSS	·	08/03/00	Abandoned	PCT	

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8	68916 1-JP	A-T- MSS	MODULAR FLUID DELIVERY. APPARATUSNguyen			Comma	
8	68916 1-KR	R ATT	MODULAR FLUID DELIVERY APPARATUSNguyen			nadar s	
89 .	68916 I-MY	Y ALT MSS	MODULAR FLUID DELIVERY APPARATUS Nguyen	n PI20020747		South Korea	
68916	916 1-SG		MODULAR FLUID DELIVERY APPARATUSNIGUYER			Makrysta	
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69013	13	MSS	FLUOROPOLYMER INTERLAYER DIELECTRIC BY CHEMICAL VAPOR DEPOSITION/Rose; Brichko; Loren:			Europe Co-owned with	
69013	13	AAT	DEPOSITION OF PLUOROPOLYMER FILMS/Mocell	n Pont)	Vinellad	Dupout	
69173	. 23	MSS	MODEL BASED TEMPERATURE CONTROL OF BATCH HIRNACED.		Thelesa		
69174	4	WESS	IN-SITU METROD AND APPARATUS FOR END POINT DETECTION IN CHEMICAL MECHANICAL OTHER PROPERTY OF THE PROPERTY OF	/628,471 /31/90	6,476,921	Co-owned with	
69174	7	MSS	IN-SITU SENSING AND ENDPOINT DETECTION IN	728.931	Zalcain.	MIT, all foreign as well	
69174	4	AT.	IN-SITU METHOD AND APPARATUS FOR END	·			
		29	POLISHINGSOLD; Lai; Oh	1221/01		Co-owned with MIT, all foreign	

I-71935/MSS (463035-828) 1059128

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MSS IN-SITU METROD AND APPARATUS FOR END 2003-7001394	₩.	£169		MSS	IN-SITU METHOD AND APPARATUS FOR END POINT DETECTION	2002-516606		China	$\dot{\Box}$
MSS	¥	69174		MGS		01/31/01	· .	undar.	
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MSS	A	69174	1	MSS		200300662-4	·	ë	· · ·
MSS IN-SITU METHOD AND APPARATUS FOR END PCT/US01/24146 Guesed POLISEIR/GNEW, Saker, Oh POLISEIR/GNEW, Saker, Oh POLISEIR/GNEW, Saker, Oh MSS APPARATUS AND METHOD FOR CHEMICAL POLISEIR/G OF SUBSTRATES/Malvin; 07/31/00 MSS APPARATUS AND METHOD FOR CHEMICAL POLISEIR/G OF SUBSTRATES/Malvin; 07/31/00 MSS APPARATUS AND METHOD FOR CHEMICAL POLISEIR/G OF SUBSTRATES/Malvin; 07/31/01 MSS APPARATUS AND METHOD FOR CHEMICAL SOLISE/G CHEMICAL POLISEIR/G OF SUBSTRATES/Malvin; 07/31/01 MSS APPARATUS AND METHOD FOR CHEMICAL SOLISEIR/G OF SUBSTRATES/Malvin; 12/29/00 Guesed Sout; Oh MASS APPARATUS AND METHOD FOR CHEMICAL GOZS9/016 Guesed Sout; Oh MASS APPARATUS AND METHOD FOR CHEMICAL GOZS9/016 Guesed Sout; Oh MASS APPARATUS AND METHOD FOR CHEMICAL GOZS9/016 Guesed Sout; Oh MASS APPARATUS AND METHOD FOR CHEMICAL GOZS9/016 Guesed Sout; Oh MASS APPARATUS AND METHOD FOR CHEMICAL GOZS9/016 Guesed Sout; Oh MASS APPARATUS AND METHOD FOR CHEMICAL GOZS9/016 Guesed Makvin; Oh MASS APPARATUS AND METHOD FOR CHEMICAL GOZS9/016 GUESTAATUS AND METHOD FOR CHEMICAL GOZS9/01	₹.	69174	1-TW	. SSW		01/31/01 90118624 07/31/01	158247. 10/18/m2	Taiwan	·
MSS APPARATUS AND METHOD FOR CHEMICAL MECHANICAL POLISHING OF SUBSTRATES/Melvin; 07/31/00 MSS APPARATUS AND METHOD FOR CHEMICAL Sw; Oh MSS APPARATUS AND METHOD FOR CHEMICAL MECHANICAL POLISHING OF SUBSTRATES/Melvin; 07/31/01 MSS APPARATUS AND METHOD FOR CHEMICAL MGCHANICAL POLISHING OF SUBSTRATES/Melvin; 12/29/00 MANS APPARATUS AND METHOD FOR CHEMICAL MGCHANICAL POLISHING OF SUBSTRATES/Sub; 01 MANS APPARATUS AND METHOD FOR CHEMICAL MGCHANICAL POLISHING OF SUBSTRATES/Sub; 01/31/01 MANS APPARATUS AND METHOD FOR CHEMICAL MGCHANICAL POLISHING OF SUBSTRATES/Sub; 01/31/01 MANS APPARATUS AND METHOD FOR CHEMICAL MGCHANICAL POLISHING OF SUBSTRATES/Sub; 01/31/01	昆.	69174	1-PC	MSS		PCI/US01/24146 07/31/01	Closed	PCT	
A 69175 MY MSS APPARATUS AND METHOD FOR CHEMICAL A 69175 TW MSS APPARATUS AND METHOD FOR CHEMICAL A 69175 TW MSS APPARATUS AND METHOD FOR CHEMICAL MECHANICAL POLISHING OF SUBSTRATES/Melvin; 07731/01 69175 1 MSS APPARATUS AND METHOD FOR CHEMICAL MECHANICAL POLISHING OF SUBSTRATES/Melvin; 1273/00 MANHEL ON MANHEL	4	69175		MSS	ä	09/628,563 07/31/00		Co-owned with	
MSS APPARATUS AND METHOD FOR CHEMICAL MECHANICAL POLISHING OF SUBSTRATES/Melvin; 07/31/01 MSS APPARATUS AND METHOD FOR CHEMICAL Sub; Oh MECHANICAL POLISHING OF SUBSTRATES/Melvin; 12/29/00 MSS APPARATUS AND METHOD FOR CHEMICAL MECHANICAL POLISHING OF SUBSTRATES/Sub; 12/29/00 MASS APPARATUS AND METHOD FOR CHEMICAL MECHANICAL POLISHING MECHANICAL POLISHING MECHANICAL POLISHING MECHANICAL POLISHING MECHANICAL POLISHING	FA	69175			RATUS AND METHOD FOR CHEMICAL ANICAL POLISHING OF SUBSTRATES Melvin;	120013601		MIT, all foreign as well Malaysia	
MSS APPARATUS AND METHOD FOR CHEMICAL MECHANICAL POLISHING OF SUBSTRATES/Melvin; 12/29/00 Sub; Oh MECHANICAL POLISHING OF SUBSTRATES/Sub; MECHANICAL POLISHING OF SUBSTRATES/Sub; Melvin; Oh MSS APPARATUS AND METHOD FOR CHEMICAL MGCHANICAL POLISHING: 0121/01	FA .	52169		·		0118623		Taiwan	
MECHANICAL POLISHING OF SUBSTRATES/Sub; AMECHANICAL BIDINGS/158 (APPARATUS AND METHOD FOR CHEMICAL 01815145.0 MECHANICAL POLISHING OF SUBSTRATES/Sub; APPARATUS AND METHOD FOR CHEMICAL 01815145.0 MECHANICAL POLISHING	Ā	52169	I		į.		Closed		
MSS APPARATUS AND METHOD FOR CHEMICAL 01815145.0 MECHANICAL POLISHING: 01/31/01					销品	M21701 128		Co-owned with	
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FA	69175	1-86	MSS	MECEANICAL POLISEING APPARATTIS AND APPARATOR TO THE AND APPARATOR AND APPARATOR TO THE AND A	2003-7001395 01/31/01		South Korea
FA	69175	<u> </u>	Mee	MECHANICAL POLISHING	200300678-0 01/31/01		Singapore
			record .	MECHANICAL POLISHING	1962336.2		Ruman
配	69175.	1-PC	MSS	APPARATUS AND METHOD FOR CHEMICAL MECHANICAL POLISHING OF SUBSTRATES/Malvin; Sub: Oh	01/31/01 PCT/US01/41513 ; 07/31/01		PCT
∢ .	69175	7	MSS	APPARATUS AND METHOD FOR CHEMICAL MECHANICAL POLISHING OF SUBSTRATES/Sub;	Closed		
¥	82269		MSS	METHOD OF CHEMICAL MECHANICAL	., ., ., .,		
FA	80208	3		FULLSHING/Lai; Saka; Oh	07/31/00	6,458,013.	Co-owned with MIT, all foreign
				MAITHOD OF CHEMICAL MECHANICAL POLISHING/Lei: Selv. O.	01815147.7		as well
FA	69228	ej.	MSS	METHOD OF CHEMICAL MECHANICAL	07/31/01		
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FA	82289	MY.	MSS	MBCHANICAL	2003-7001400 07/31/01 pro012402		South Korea
£;	82289	2	MSS	METHOD OF CHEMICAL MECHANICAL	07/31/01.		Malaysia
FA	82289	8	MSS		07/31/01		PCT
	69228	W.I	MSS	METHOD OF CHEMICAL MECHANICAL POLISHMA/1 - 5-1-0-0-0-0-0-0-0-0-0-0-0-0-0-0-0-0-0-0-	2000003-2 07/31/01 90118625		Singapore
出	82228	EI ·	MSS		07/31/01		Taiwan
	69229	24	MSS	MAL REMOVAL IN THE	13	Closed	· · · · ·
925 8218	F-71935/MSS (463(035-828) 1059128	(828-52)			105270		
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				Lei; Salz; Chm	Fuling Date	Issue Date	Countries	
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				OXIDE DAMASCENE STRUCTURES/Sakai; Lai; Oh	01/23/02		Co-owned with	1
<u></u>	63259	2	MSS	CHEMICAL MECHANICAL POLISHING OF COPPER.	PCT/ITSM/mms4		as will	
4	69274	1	MSS	METHOD AND A PPA DATE TO THE STATE OF	01/23/02		PCT	
			•	WAFERS BETWEEN CASSETTES AND A BOAT, Highes, Webber, Herlinger, Nighterm: Schemen.	06/864,077 05/16/86	4,770,590 09/13/88		
2	69274	:	. SSW	METHOD AND APPARATUS FOR TRANSFERRING WAFERS BETWEEN CASSETTES AND A BOAT/ Finches Webber Hading	90/006,018 05/21/01	Re-examination of Patent No. 4.770 590		· · · · · · · · · · · · · · · · · · ·
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					P3715601.2 05/09/87	31 <i>5787.</i> 07/06/00	Germany	·
FA	69274	DB-1	MSS		P3745134 0			
				_	01/24/96	03/04/99	Germany	
۲.	69274	E.	. SSW		8706851	8706851		
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FA	69274	A .	MSS	METHOD AND APPARATUS FOR TRANSFERRING 6	62-117197			
FA	69274	₩	MSS	g	05/15/87	,	mater	
•				WAPERS BETWEEN CASSETTES AND A BOAT/ Enghor, Webber, Herlinger, Nightlenger, School	8711230 05/13/87	2190345	Great Britain	
₹	69274		SSM		8922730.0			
	1					08/12/90	Great Britain	•

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				Title/Inventors	Serfel No /			
4	504.04	3	MSS	NON-CONTACT CAP MACHINE	Fiffing Darto	Issue Date	Foreign Countries	l
۵	69,623	1				CLOSED PER		
4.	<u> </u>	· 	MSS	SYSTEM AND METHOD TO CONTROL RADIAL	60/274 532	T WESTERN		
K	69447	121	MSS	SYSTEM AND METHOD, TO CONTROL PAPIAT	03/08/01			
E:	69447	7 PC	MSS	SYSTEM AND METHOD TO CONTROL PARTY	10/095,974 03/08/02			
FA	69447	20	MSS	SYSTEM AND METHOD TO CONTROL BADIAL	PCT/US02/07034 03/08/02	141	PCT	
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FA	69447	K	MSS	SYSTEM AND METHOD TO CONTROL PARTIES	2002/572612 03/08/02		Japan	
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FA	69447	SG.	MSS	SYSTEM AND METHOD TO CONTROL RADIAL	06/28/02 200706968_n		Malayaia	
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F18	69447	畠	MESS	SYSTEM AND METHOD TO CONTROL RADIAL	06/25/02		Taiwan	
	69448		MSS	INERTIAL TEMPERATURE CONTROL/Starner		-	Burope '	
. ¥	69448		MSS	INERTIAL TEMPERATURE CONTROL/Sumer		- Togge	·	
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FA	69448	TW	MBS	NERTIAL TRADER ATTER COMME	02/06/02		Singapore	
E	60440	_		THE TRANSPORT OF THE CONTROL STREET	91101797	173549	Taiwan	
3	9	· 날	SSW	INERTIAL TEMPERATURE CONTROL/Sterner	02250814.7	07/07/03		
∢.	69477	Ŀ	MSS	NON-CONTACT CAP MACERIER	02/06/02		Europe	1
<u>A</u>	62869		MESS	APPARATIS ROP THE INTERIOR		Closed.		
				DEPOSITION OF TBOS+03 BASED SIOX THIN FILMS ON SIT IOON STREET, CLE	60/335,494 11/01/01	Closed		- 1
	·			SILICON-MITRIDE SURFACES/Mayer, Ingle; Murphy; Matton: Kurita				
₹	62869		MSS	APPARATUS FOR THE PRHFHRENTIAL				
				DEPOSITION OF TROSHO3 BASED SIOX THIN	10/285,966			
				SUICON-WIRIDE SURFACES/Mayer; Ingle; Murphy:		,		
FA	60820	2		Community College		•	· .	
			MBG V	DEPOSITION OF TEOSHO3 BASED SIOX THIN	11/01/02		China	1
				SULCON-NITRIDE SURFACES/Mayer, Ingle: Murphy;		. •	•	
FA	62869	Ei,	MSS.					
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		·		SILICON-NUTRIDE SURPACES/Mayer, Ingle; Murphy;				
¥.	62869	E E	MESS	APPARATUS FOR THE PREFERENTIAL				
					10/31/02		South Korea	
			· F4	Matteon; Kurita Matteon; Kurita				
FA	69829 N	MY IN						
•	:	9 # 2	MBG	FILMS ON SILICON SURPACES RELATIVE TO	10/28/02		Malaysia	. •
			n A	MILICON-MITRIDE SURFACES/Mayer, Ingle, Murphy,	•		··.	
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				Title/Inventors	Sertal No.	Pirture No.		
<u> </u>	62869	98 6	MESS	APPARATUS FOR THE PREFERENT AT	Filing Date	Isrue Date	Countries	
			N D D	PILMS ON SILICON SURFACES RELATIVE TO	200206557-1 10/28/02		Singapore	T
<u>. </u>				Matteon; Kurin				
₩	8823	T T	l	APPARATUS FOR THE PREFERENTIAL				_
· 	· 		NBG V	PILMS ON SILICON SURPACES RELATIVE TO	10/25/02		Taiwan	
		_		Mathon; Knrin				
岳	69828	닯	1	APPARATUS FOR THE PRHERRHUTTAT		:		
.•	· .	,	MBG	DEPOSITION OF TEOS+03 BASED SIOX THIN FILMS ON SILICON SURFACES RELATIVE TO	01/01/02		Burope	
				SELICON-NITRIDE SURPACES/Mayer; Ingle; Murphy; Methon; Knits.				
<u>.</u>	70028		MSS	MULTILAYER HIGH DHI BCTBIC COME				
I∢	70078	\perp	, June	OXIDE FILMS AND METHOD OF MAKING/Senzaki	60/264,428 01/26/01	Closed		
			2016	MULTILAYER HIGH-x GATE OXIDE THIN	10/056.625	•		
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	•			Treat, Brichto, Lopan, Rose	60/288,653	Closed	Application is co-	
		•			05/04/01		DuPont	
			Cocoo	PLUOROPOLYMER INTERI AVER PIET BOTTEL			To be filed by	
			manber.	CHEMICAL VAPOR DEPOSITION/Lopata; Mocella	10/137,875 May 2, 2002		Application is co-	
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e,	70380		MSS	H A I TOTIES			To be filed by	
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<u> </u>	7.0380	NAY.	MSS I	STEM AND	11/27/02 P1 2002434			
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	This/Inventors	HIGH FLOW RATE BUBBLER SYSTEMAND	HIGH FLOW RATE BUBBLER SYSTEM AND	ABLAN America	SEAL IN A PROCESS CHAMBER/Draper, Robinson;	APPARATUS & METHOD FOR INSULATING A SEAL	APPARATUS & METHOD FOR INSULATING A SHAL	APPARATUS & METHOD FOR INSULATING A SEAL	APPARATUS & MEHOD FOR INSTITUTION	IN A PROCESS CHAMBER/Draper, Robinson; Lopes APPAPATITE A LEARNING A LOPES	IN A PROCESS CHAMBER/Draper: Robinson: I one	APPARATUS & METHOD FOR INSULATING A SEAL IN A PROCESS CHAMER	SYSTEM AND METHOD FOR DEPOSITIVE	INORGANICORGANIC DIBLECTRIC FILMS/Draper;	APPARATUS & METHOD FOR INSULATING A SEAL IN A PROCESS CHAINS AS SEAL	CHEMICAL VAPOR DEPOSITION SYSTEM FOR	MODULAR INTECTOR AND EXHAUST ASSEMBLY/	_	7	Matthiosen; Kmin
		SSSW	MSS	MSG	WEN	MEN	MSS	MSS	MSS	MSS .		MSS	15		MSS	MSS	MSS	MSS		MBG
Š		ML os	02 PC	+	· .		3	<u>e</u>	K	¥¥	$\neg \neg$	හි .	2		岛				F	
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		Foreign Countries	Japan	·	South Korea	Millaveia		Singapore		Taiwan	•	Burope		[related opened	Anni # MV.	0P120021354	TW-091107447;	١	rC1/EP02/04060]		•		China		Jones		
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	Title/Inventors	MODULAR INJECTOR/DeDondey; Mathiesen: Kurite		MODULAR INIECTOR DeDontley; Matthiesen: Krnit-		MODULAR INIECTOR DeDontiey; Matthiesen; Kurita	MODULAR INJECTOR De Dentiere Manuel	Kimis Kimis	MODULAR INIBCTOR/DeDonilger Metti	Authority, Authority, Authority	MODULAR INIBCTOR/Dedoutley: Mathiesen:	HEATING SYSTEMS	AN ATMOSPHERIC DE CONTROL BOR HEATING	Koestler					DEPOSITION OF LOW STRESS GERMANIUM AND BORON PORTS OF TO	WAVEGUIDES/Mosseri	OXIDE STRUCTURE AND METHOD OF FORMING	,	WAVEGUIDE AND METHOD OF FORMING THE	ALDE STRUCTURE/Mognard		4 .	
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		·	WAVEGUDE AND METROD OF FORMING THE OXIDE STRUCTURE/	PIZ0022907 08/02/02		Malaysia	
<u> </u>	70859. SG	MSS	OXIDE STRUCTURE USEABLE FOR OFTICAL WAVEGUIDE AND METEOD OF FORMING THE	200204671-2 08m2m2		Singapore	
70859	59 TW.	MSS	OXIDE STRUCTURE USEABLE FOR OPTICAL WAVEGING AND	91117477		·	
70859	S9 EP	MESS	OXIDE STRUCTURE/ Mogard DRPOSTTON OF CORNING THE	08/02/02		Taiwan	
		MDV	BORON DOPED SILICA FILMS FOR OFTICAL WAVEGUIDESMANNEL	02255429.9 08/02/02		Burope	
70888	.88 88	SSIM HTT	BELLOWS ROTARY FEED-THROUGH SEAL/ Ha	Closed			-
70893	83	MSS	AN IMPROVED DESIGN FOR A LINEAR INJECTOR ASSEMBLY/Mattson; Hakimelahy; Bartholomew; Part; Yuh	60/314,762 08/24/01	Closed		
70893	8	MSS		10226,459			
70893	3 147	MSS		PIONOSIOA			
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70893	δ. Σ			08/23/02 PCT/US02/27376 08/26/07		Taiwan PCT	
70896		MSS	ATMOSPHERIC PRESSURE WAFER PROCESSING REACTOR HAVING AN INTERNAL PRESSURE CONTROL SYSTEM AND METHOD/Bartholomew; Bailey, Park: York	0	Closed		
70896		NCSS	ATMOSPHERIC PRESSURE WAFER PROCESSING IN	10/226,773			
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7, 5794	Ittle/Inventors	SYSTEM AND METHOD FOR IMPROVED THIN DIELECTRIC FILMS/Senzaki; Hering: Heling: Osberne	OPTIMIZATION OF CHEMICAL BRACHONE AND	COMPUTER STATIONS AND COMPUTER STATIONS AND COMPUTER STATIONS AND COMPUTERS STATIONS AND COMPUTERNY APPROACH OF THE APPROACH O	HEATED VACUUM SUPPORT APPARATUS	HEATED VACUUM SUPPORT APPARATUS/Kme:	HEATED VACUUM SUPPORT APPARTUS: Kana	HEATED VACHIN STEPPER AND STEPPER	Balley; Kurin; Voock	HEATED VACUUM SUPPORT APPARATUS/Kane; Bailoy, Kurin: Vocci	IN-SITU THERMAL CHAMBER CLEANING/Berning	SINGLE WAFER THERMAT BEATHERMAN	AND IN-SITU CLEANING METHOD/Henting, Sisson;	SINGLE WAFER THERMAL PROCESSING SYSTEM	Serzald:	AND IN-SITU CLEANING METHOD/Hering; Sisson;			APPARATISHES III S.
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e,	71638		MSS	OF HIGH-k	07/19/02 60/396,723		,	
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A	71644		MSS	IN-SITU FORMATION OF MIM CAPACITORS/Same-In Addition	Filling Dette	Large Date	Foreign Countries	
FA	71644	TW	MSS	IN-SITU FORMATION OF VIEW CASE	07/19/02	Closed		T
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				NILICATES FOR HIGH-K GATE AND CAPACITOR DIFFERENCES/Sang-In Les; S.K. Lee; Shin; Sensel;	08/18/03	•	PCI	
4	1172		MSS	LOW TRAPERATURE DEPOSITION OF SELICON OXIDES AND SELICON OXYNITRIDE/Sang-In Loc;	60/404,363	Closed		
∢	7772		MSS	LOW TEMPERATURE DEPOSITION OF ANY	·		•	
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2 774	130s/Inventors	SEQUENTIAL TWO-STEP ATOMIC LAYER DEPOSITION OF COPPER SEED LAYER	SEQUENTIAL TWO-STEP ATOMIC LAYER	TWO-STEP SEQUENTIAL GROWTH OF HIGH-K	DEPOSITION/Senzald TATOMIC LAYER ANNIA PROCESSOR	DIELECTRIC THIN FILMS/Sezzaki; Brichko	THERMAL PROCESSING SYSTEM AND CONFIGURABLE VERTICAL CHAMBER P. D	HERMAL PROCESSING SVSTEM AND	CONFIGURABLE VERTICAL CHAMBER/DuBois; Nam; Wildman; Qui; Kowalski	HERMAL PROCESSING SYSTEM AND SONFIGURABLE VERTICAL CEAMBER/DuBois:	RDESTAL THERMAL SHIELD/Wildman; Qui	THERMAL PROCESSING APPARATUS AND METHOD OF BACKETING A CTANGET	CLEANING/Tortumen THERMAL PROCESSING APPARATUS AND METHOD OF BACKET		CKFILING A CHAMBER	VACUUM ASSEMBLY WITH MULTI-STAGE VALVE SEQUENCE ON	
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₹ .	71752		MESS	CYCLONIC COOLING SYSTEM AND METHOD/Qui; Collins	07/10/03			
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<u>E</u>	71.752	<u>ي</u>	MSS	CYCLONIC COOLING SYSTEM AND METHOD/Qui;	0//10/03		PCT	
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<u> </u>	71754		MSS	FRED FORWARD TEMPERATURE CONTROLLERIMA	with 71752.			
∢	71755		MSS	ALIGNMENT APPARATUS AND METHOD OF ALIGNING A WAFER MA	Closed		·.	
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¥	71757		MSS.	DISTRIBUTED SINGLE WIRE NETWORKING BLEVATOR CONTROL SPECIAL				
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	71758		MSS	LOAD PORT; Jeffery E. Kowalski				
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Titie/Inventors	LOAD PORT APPARATUS; Jeffery B. Kowalski	THERMAL PROCESSING CHAMBER ENVIRONMENTAL CONTROL SYSTEM AND METHOD; Alm Stemer	CONTROL OF A GASEOUS ENVIRONMENT IN A WAFER LOADING CHAMBER; Alsn Stemen	CONTROL OF A GASEOUS ENVIRONMENT IN A WAFER LOADING CHAMBER; Alsn Stemet	METHOD AND SYSTEM FOR ISOTHERMAL HEATING OF WAFERS; Jeffey Kowalski	HEATER H.EMENT SH. ECTABLE FOR VARIABLE TEMPERATURE PROCESSING/Qui			T-RAIL SUPPORT/DaBois	METHOD & AFPARATUS FOR SUPPORTING SEMICONDUCTOR WAFFRSOn SOFT	RTING	FEED FORWARD CONTROL SYSTEM AND METHOD/Todomm; Radiff (This case may be related to A-71754)	SYSTEM ARCHITECTURE AND METEOR FOR
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		HT.	DIRLECTRICS/Senzald; Bereaw; Chatham; Higushi; Lopeta	60/424,891 11/08/02			
7	71824	MSS	REMOTE PLASMA NITRIDATION OF HIGH-K GATE DIFT ECTRICS/Senzaki; Bercaw; Chatham; Higuchi; Lopata				
71,	71884	MSS	METHOD OF ATOMIC LAYER REMOVAL OR BLEACHING/Sing-in Lee	Closed, combined			
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72332	22	MSS	IN-SITE CLEANING OF COPPER DETECTION CHAMBER & PARTS			D-2493	••
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734	4	MSS	BATCH FURNACE WAFER RADIAL DELTA TEMPERATURE CONTROL USING A BOTTOM AND				
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